

Approved : Yoshimichi Hirokawa
Yoshimichi HirokawaPrepared : Takeshi Usuda
Takeshi Usuda

No.	Test item	Conditions	Conditions of acceptability	Result
1	High temp./overload test	(1) Input : Max.voltage, Min.voltage (2) Output : Overload (3) Test period : 48 hours (4) Testing circuit Fig.1~Fig.4	(1)Power supply is not failed.	ok
2	High voltage input test	(1) Input : 1.35 times of rated voltage (2) Output : Rated output (3) Ambient temp. : $25 \pm 10^{\circ}\text{C}$ (4) Testing circuit Fig.1~Fig.4	(1)No smoke, no fire.	ok
3	Low voltage input test	(1) Input : Min. regulation voltage (2) Output : Rated output (3) Ambient temp. : $25 \pm 10^{\circ}\text{C}$ (4) Test period : 48 hours (5) Testing circuit Fig.1~Fig.4	(1)Power supply is not failed.	ok
4	Input ON/OFF test	(1) Input : Max.voltage T= 2sec Duty= 50% (2) Output : Rated output (3) Ambient temp. : $25 \pm 10^{\circ}\text{C}$ (4) ON/OFF period : 1,000 (5) Testing circuit Fig.1~Fig.4	(1)Power supply is not failed. (2)The surge current of each components should not exceed the rated value.	ok
5	Output ON/OFF test	(1) Input : Rated input (2) Output : 0% \longleftrightarrow 100% T= 2sec Duty= 50% (3) Ambient temp. : $25 \pm 10^{\circ}\text{C}$ (4) ON/OFF period : 1,000 (5) Testing circuit Fig.1~Fig.4	(1)Power supply is not failed.	ok
6	Output-short start test	(1) Input : Max.voltage (2) Output : Short start (3) Ambient temp. : $25 \pm 10^{\circ}\text{C}$ (4) Testing circuit Fig.1~Fig.4	(1)Power supply is not failed.	ok
7	Output short test	(1) Input : Max.voltage (2) Output : Short (3) Ambient temp. : $25 \pm 10^{\circ}\text{C}$ (4) Test period : 48 hours (5) Testing circuit Fig.1~Fig.4	(1)Power supply is not failed.	ok
8	Vibration/impact test	Vibration (1) $f=10 \sim 150\text{Hz}$: 49.0m/s^2 (2)3 minutes period (3)60 minutes along X, Y and Z axis Impact (1) 294.2m/s^2 11ms (2)Once each X, Y and Z axis	(1)No degradation of electric characteristics after test. (2)No crack at solder joint. (3)No marked damage of appearance.	ok

○ Testing circuitry

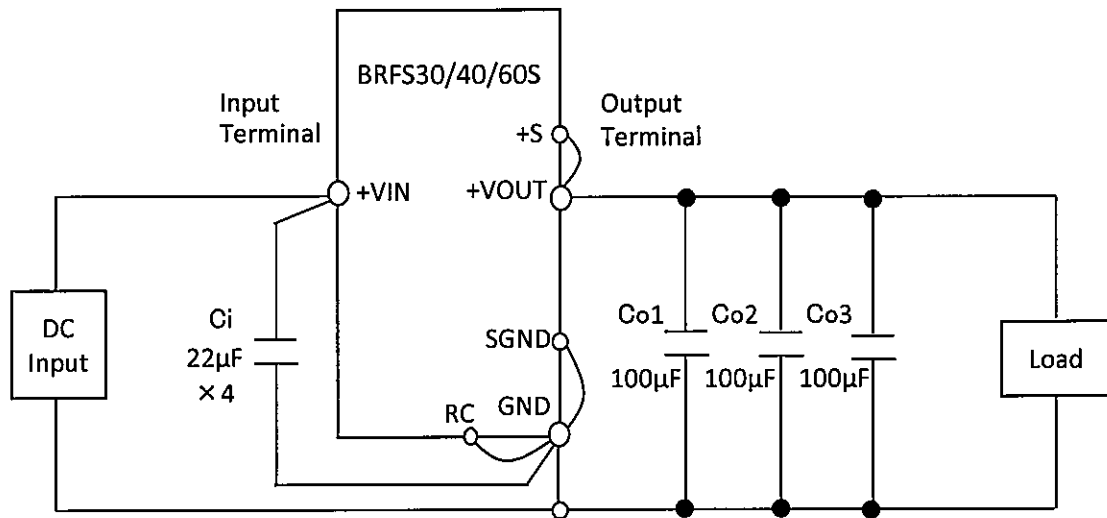


Fig.1 Testing circuitry (BRF30/40/60S)

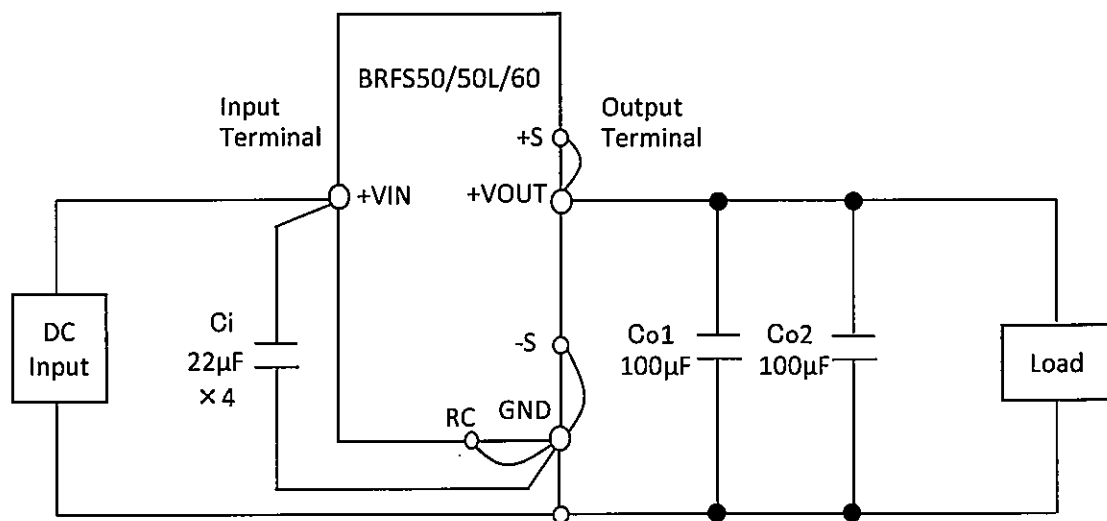


Fig.2 Testing circuitry (BRF50/50L/60)

○ Testing circuitry

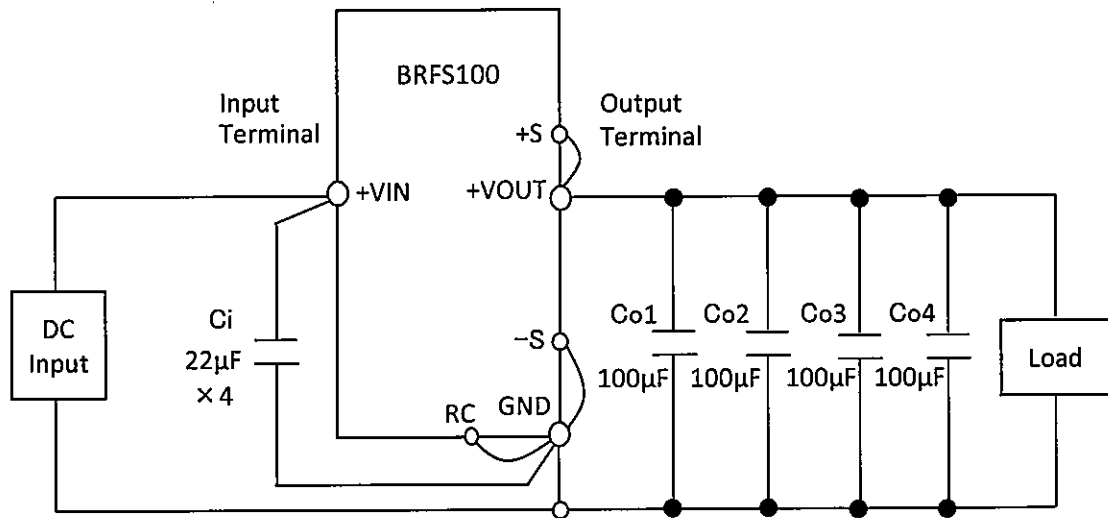


Fig.3 Testing circuitry (BRF5100)

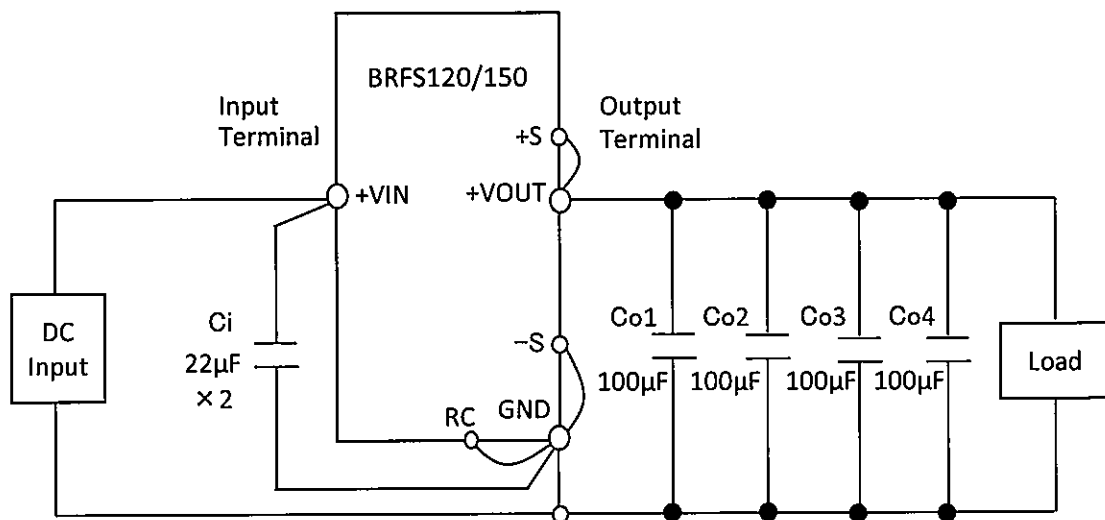


Fig.4 Testing circuitry (BRF5120/150)